

# Lecture 15

## The pn Junction Diode (II)

### Outline

- I-V characteristics
  - Forward Bias
  - Reverse Bias

### **Reading Assignment:**

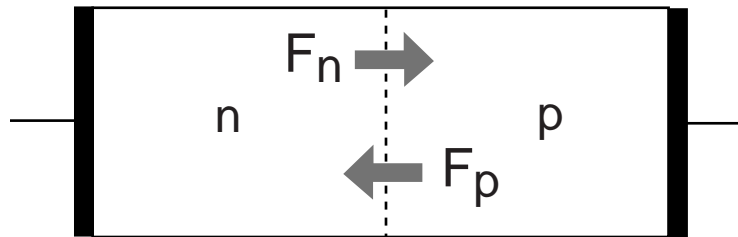
Howe and Sodini; Chapter 6, Sections 6.4 - 6.5

## 1. I-V Characteristics (contd.)

Diode Current equation:

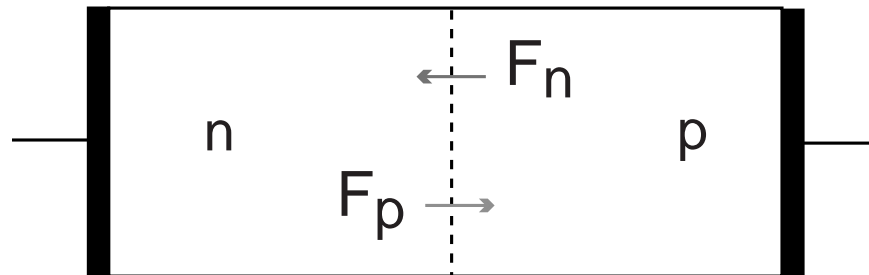
$$I = I_o \left( e^{\left[ \frac{v}{V_{th}} \right]} - 1 \right)$$

Physics of forward bias:



- Potential drop across SCR reduced by V
  - $\Rightarrow$  minority carrier injection in QNRs
- Minority carrier diffusion through QNRs
- Minority carrier recombination at contacts to the QNRs (and surfaces)
- Large supply of carriers injected into the QNRs

$$\Rightarrow I \propto e^{\left[ \frac{v}{V_{th}} \right]}$$

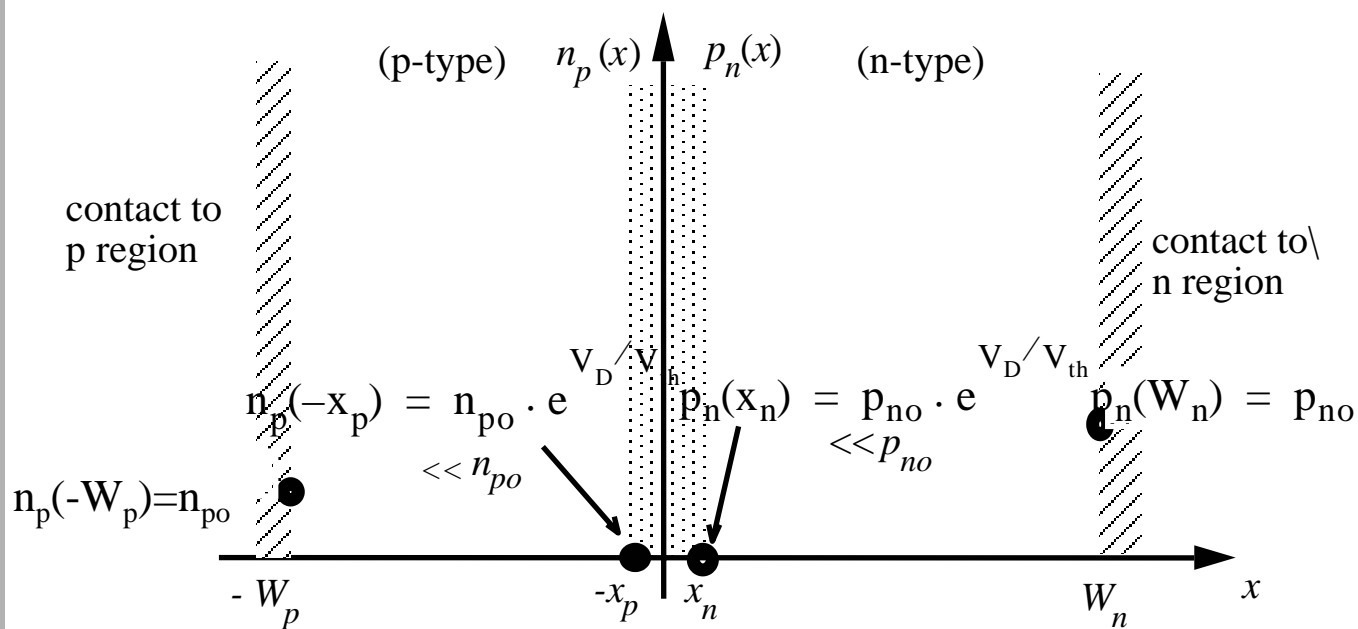


### Physics of reverse bias:

- Potential drop across SCR increased by  $V$ 
  - $\Rightarrow$  minority carrier extraction from QNRs
- Minority carrier diffusion through QNRs
- Minority carrier generation at surfaces & contacts of QNRs
- Very small supply of carriers available for extraction
  - $\Rightarrow$   $I$  saturates to small value

## Development of analytical current model:

1. Calculate the concentration of minority carriers at edges of SCR;
2. Find the spatial distribution of the minority carrier concentrations in each QNR;
3. Calculate minority carrier diffusion current at SCR edge.
4. Sum minority carrier electron and hole diffusion currents at SCR edge.

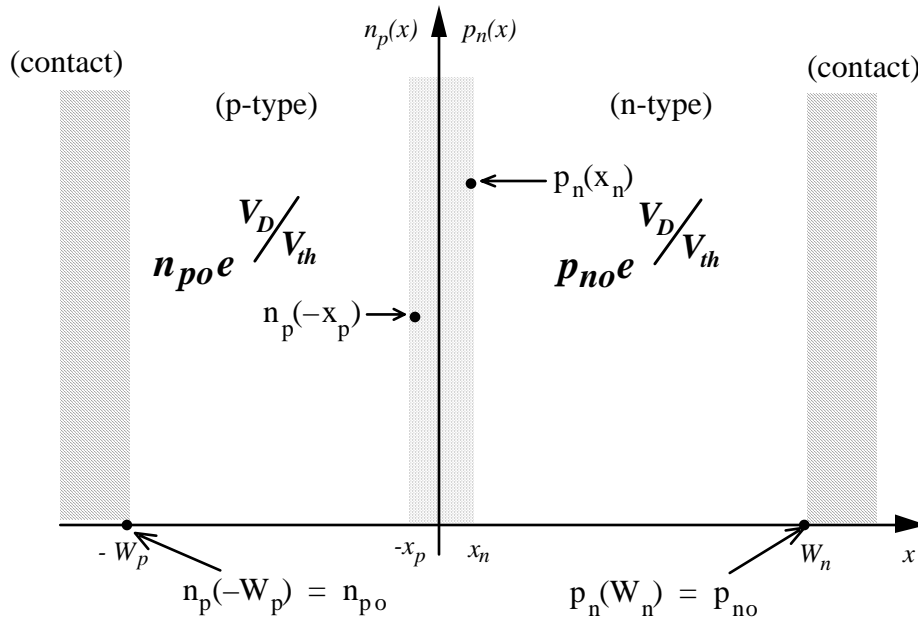


Reverse Bias

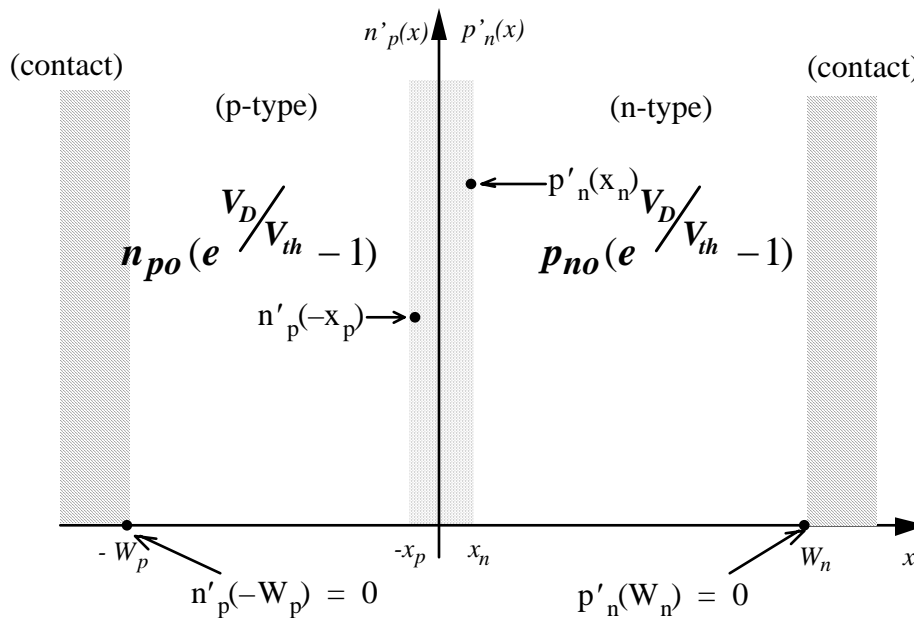
# Total and Excess Concentrations

## Forward Bias (Step 1)

Total Carrier Concentration (n & p)

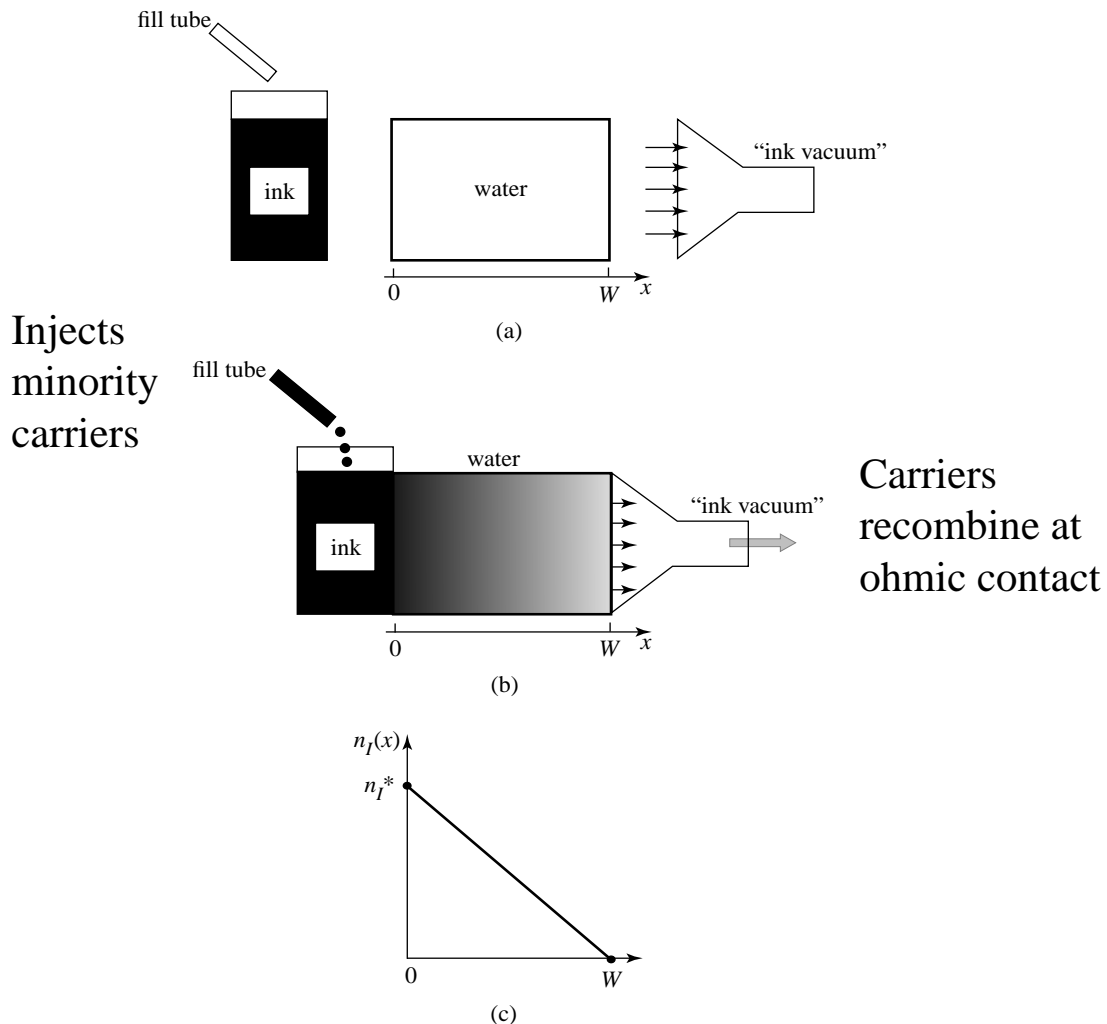


Excess Carrier Concentration (n' & p') - Subtract  $n_{p0}$  and  $p_{n0}$



# Steady-State Diffusion Ink Diffusion Example

- Flux is number of ink molecules passing a plane/cm<sup>2</sup>-sec
- No molecules vanish in the water (**NO recombination**)
- Ink concentration is a constant at  $x = 0$
- Ink concentration is zero at  $x = W$  (**ohmic contact**)
- Result - Ink concentration falls **linearly** from  $x=0$  to  $x=W$

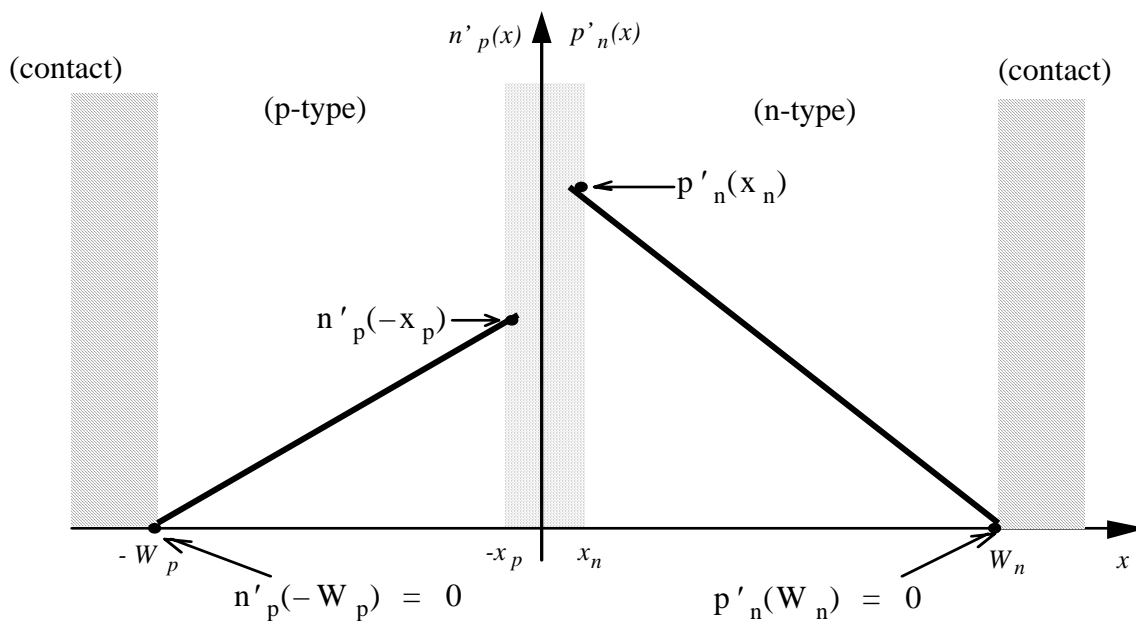


# Minority Carrier Spatial Distribution (Step 2)

- Concentration linearly decreases from SCR edge to ohmic contact. The expressions assumes **no recombination** in the QNR.

$$n'_p(x) = n'_p(-x_p) + \left( \frac{n'_p(-x_p)}{W_p - x_p} \right) \cdot (x + x_p)$$

$$p'_n(x) = p'_n(x_n) - \left( \frac{p'_n(x_n)}{W_n - x_n} \right) \cdot (x - x_n)$$



Steady-state---> minority carriers are **continuously injected** across the junction to maintain the value at the SCR edge set by the applied bias. The **same number continuously recombine** at ohmic contact.

## Minority Carrier Diffusion Current at SCR Edge (Step 3)

- Gradient in minority carrier concentrations across the n & p QNRs
- $n = n_o + n' \rightarrow dn/dx = dn'/dx$
- Transport occurs by diffusion
- Ignore drift component since minority carriers

At  $-x_p$  electron diffusion current:

$$J_n = qD_n \frac{dn'_p}{dx} = qD_n \left( \frac{n'_p(-x_p) - 0}{W_p - x_p} \right)$$

$$J_n = qD_n \left[ \frac{n_{po} (e^{\left[ \frac{v}{V_{th}} \right]} - 1)}{W_p - x_p} \right]$$

$$J_n = q \frac{n_i^2}{N_a} \cdot \frac{D_n}{W_p - x_p} \cdot \left[ e^{\left( \frac{v}{V_{th}} \right)} - 1 \right]$$



## Sum minority carrier diffusion currents at SCR edge (Step 4)

Hole diffusion current at  $x_n$  by same reasoning:

$$J_p = q \frac{n_i^2}{N_d} \cdot \frac{D_p}{W_n - x_n} \cdot \left[ e^{\left(\frac{qV}{kT}\right)} - 1 \right]$$

$$J = J_n + J_p = qn_i^2 \left( \frac{1}{N_a} \cdot \frac{D_n}{W_p - x_p} + \frac{1}{N_d} \cdot \frac{D_p}{W_n - x_n} \right) \cdot \left[ e^{\left(\frac{qV}{kT}\right)} - 1 \right]$$

Current is:

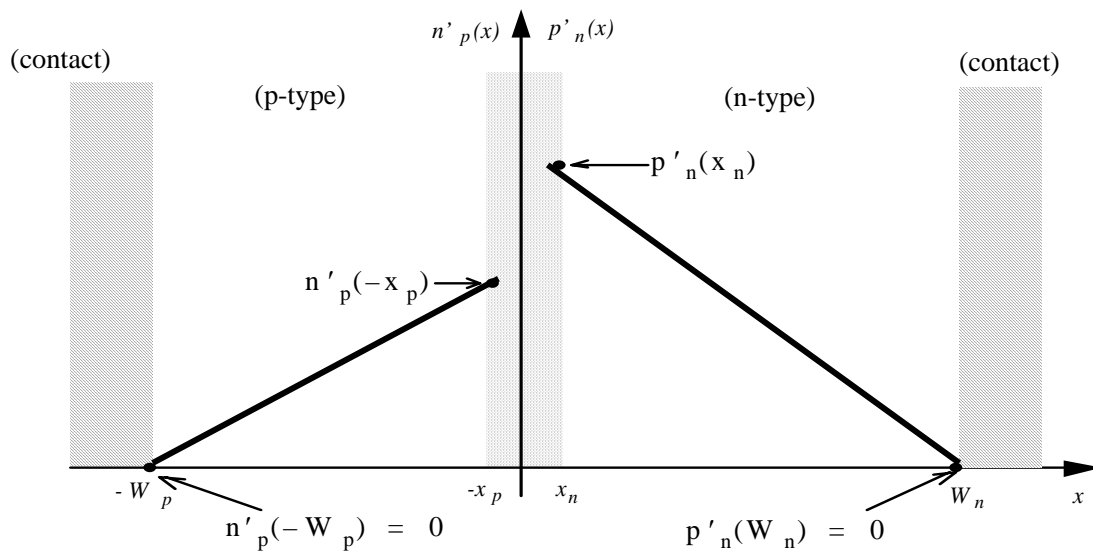
$$I = qAn_i^2 \left( \frac{1}{N_a} \cdot \frac{D_n}{W_p - x_p} + \frac{1}{N_d} \cdot \frac{D_p}{W_n - x_n} \right) \cdot \left[ e^{\left(\frac{qV}{kT}\right)} - 1 \right]$$

Often written as:

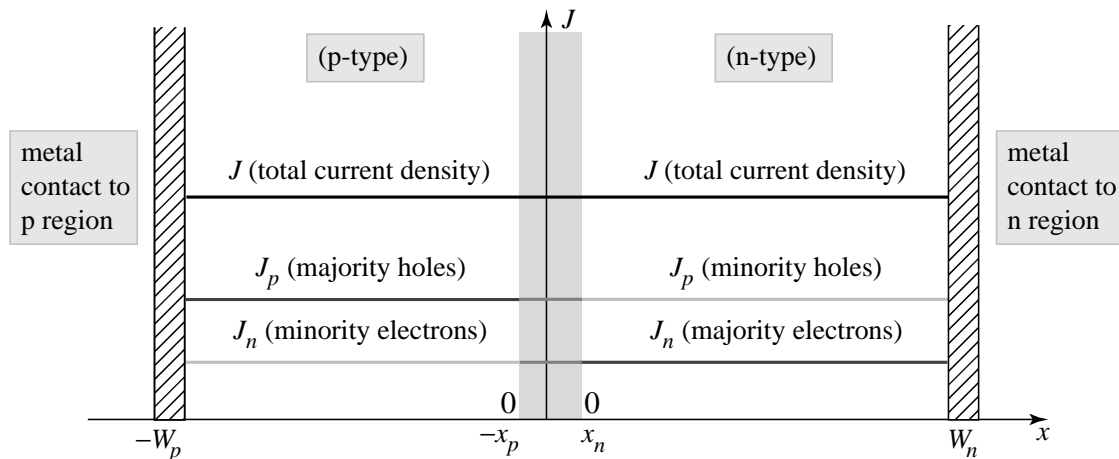
$$I = I_o \left[ e^{\left(\frac{qV}{kT}\right)} - 1 \right]$$

# Picture of Total Diode Current Forward Bias

- Minority carriers are **injected** from the other side of the junction
- Minority carriers diffuse from SCR edge to the ohmic contact with **no recombination and recombine at contact**
- Total current found by summing the minority carrier diffusion currents at SCR edges and assuming **no recombination in SCR**

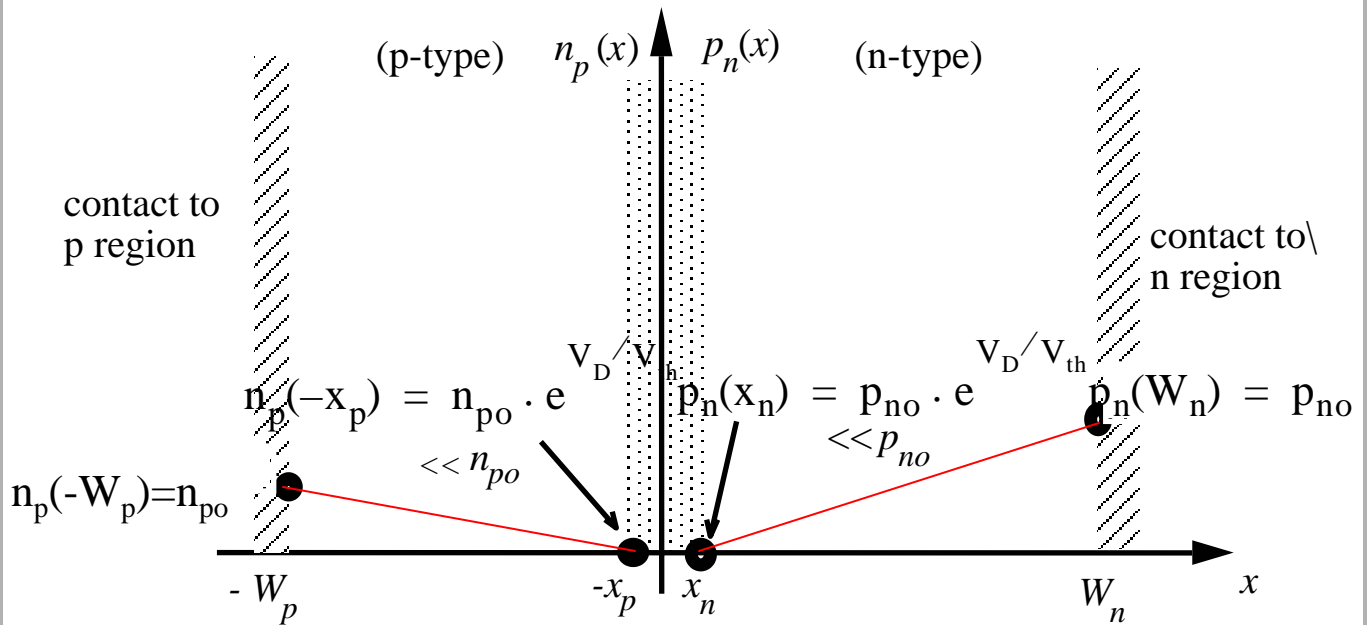


- **Majority carriers** are transported to the junction from the ohmic contact by **drift and diffusion**.



# Minority Carrier Spatial Distribution ( Reverse Bias)

- Diode current derivation same for forward and reverse bias. (same equations for spatial distribution)
- Minority carrier concentration at SCR is near zero under reverse bias.
- Concentration linearly **increases** from SCR edge to ohmic contact.
- Minority carriers flow from contacts to SCR and are swept across the junction.

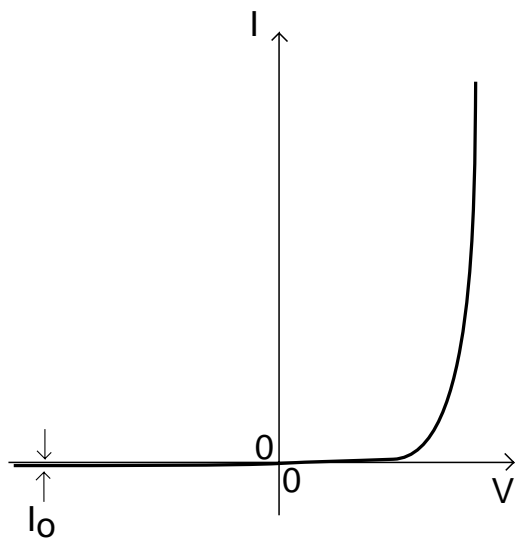


Steady-state---> minority carriers are **continuously extracted** across the junction to maintain the value at the SCR edge set by the applied bias. The **same number continuously are generated** at ohmic contact.

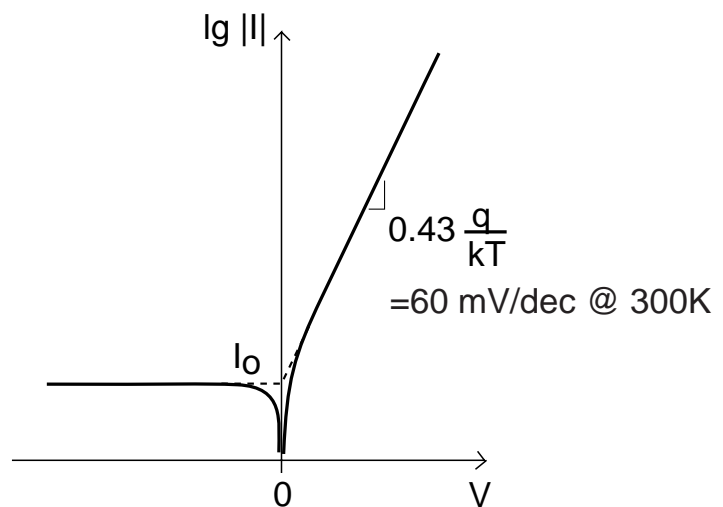
## I-V Characteristics

Diode Current equation:

$$I = I_o \left[ e^{\left( \frac{V}{V_{th}} \right)} - 1 \right]$$



linear scale



semilogarithmic scale

# What did we learn today?

## Summary of Key Concepts

- *Diode Current can be analytically determined by summing the minority carrier current at both sides of SCR*

$$I = I_o \left( e^{\left[ \frac{qV}{kT} \right]} - 1 \right)$$

- *Under forward bias:*
  - *Minority carriers are **injected** across the junction and diffuse to the contact where they **recombine***
- *Under reverse bias:*
  - *Minority carriers are **generated** at the contact and diffuse to the junction where they are **extracted** across the junction*